

**Search Notes**

Application/Control No.

10/617,817

Examiner

Roberto Velez

Applicant(s)/Patent under  
Reexamination

TERAISHI, TOSHIO

Art Unit

2829

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search:(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) Text Search (See Search History)	8/14/2007	RV